Cooler Material Reliability Considerations for Bare Die Impingement Cooling in Package

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Symposium on Reliability for Electronics and Photonics Packaging

HETEROGENEOUS INTEGRATION ROADMAP

The challenge of high-density heterogeneous integration: getting the heat out, so devices can operate reliably with a long lifetime.

- The Thermal Chapter of the HI Roadmap looks out 5 to 10 years, anticipating the needed development of cooling technologies
- > You can download chapters from the Roadmap (free) at eps.ieee.org/hir
- For more detailed reliability aspects of electronics/photonics packaging, consider attending the Symposium on Reliability for Electronics and Photonics Packaging, Nov. 16-17 (in-person and virtual): attend.ieee.org/reppp





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Topic I: Materials, Processing, and Architecture **Development for Semiconductor Packaging**



Wei et al., IEEE EMAP, 2012: 1-5.



Wei, et al., IEEE EPTC 2014: 601-605.



3µm TSV from via etching and CMP

Topic 2: Chip and Package Level Electronic Cooling: Two-Phase Jet Cooling and Microchannel Cooling



Key goal: Solving fabrication challenges in semiconductor packaging and assembly, and associated heat transfer problems



Porous

Cell id X

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structures

OUTLINE

- Background and introductions
- Material considerations and selections
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- Other cooling reliabilities: clogging, corrosion...





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State of the art liquid cooling for high performance system



Direct liquid jet cooling on the chip can eliminate the thermal resistance of thermal interface material!





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Bare die impingement cooling in package

Existing technology options:



Advantages:

- Direct cooling \rightarrow Eliminate TIM thermal resistance
- Parallel type cooling \rightarrow Reduce temperature gradient
- Deliver high localized heat transfer rates → Hotspot targeted cooling
- Multiple jet array \rightarrow Temperature uniformity

Our target:

- Customizable nozzle array to match chip power map
- Low-cost fabrication method: 3D printing
- Goal: one part solution cooling integrated in chip package







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Modeling methodologies for optimal cooler design



Unit Cell model modeling \rightarrow Larger diameter

Wei et al., Appl. Therm. Eng., 2020: 115767.

di/L=0.1

di/L=0.05

di/L=0.025

20

10

Coefficient of performance:

 $COP = \frac{Cooling \ Power}{Required \ pump \ power} = \frac{Max \ allowed \ temp \ increase/R_{th}}{Required \ pump \ power}$



d_i/L: inlet diameter ratio N×N: total inlet jet number = A/(L*L)

For a constant flow rate:

- Higher inlet diameter ratio d_i/L has larger COP
- Inlet nozzle number N between N=6 and N=8 shows optimal COP
- Making the required diameters compatible with additive manufacturing fabrication methods



0

10000

1000

100

10

1

0.1

Coefficient of performance (-)



40

Inlet jet row number N (-)

30

di/L=0.4

di/L=0.3

di/L=0.2

FL=0.53 L/min

50

60

Chip area=A

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Full cooler level modeling \rightarrow cooler material



- Negligible impact of cooler material thermal properties
- Enables low-cost fabrication technologies \rightarrow polymer-based jet cooler





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Bare die microjet cooling in packaging benchmarking



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Cooler reliability considerations

During cooler assembly

- Cooler assembly options:
 - I. First assemble package to board, then mount cooler on package (glue, clamping, ...)
 - \rightarrow No harsh temperature requirement for cooler material
 - First mount and seal cooler on package, then assembly package with cooler on PCB
 → Cooler assembly needs to survive reflow temperature (250°C)
- Property: Heat deflection temperature HDT *the temperature at which a plastic deforms under a specified load (e.g. 0.45 MPa)

Ideal material: HDT > 250°C

Ideal material: CTE matched

During cooler operation

- High reliability required for thermal cycling
- Property: Coefficient of thermal expansion CTE





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with package substrate

Polymer based 3D printing (1)

Stereolithography (SLA) used for fabrication of demonstrators

- UV exposure of *liquid resin* (acrylic based thermosetting polymer)
- Material: Somos Watershed UX 11122 (DSM) (link)
- Typical properties do not meet requirements
 - CTE: 100 150 ppm/°C
 - HDT: 45 60°C
- Recent material developed:
 Formlabs FLHTAM01 High Temp Resin (link)
 - Interesting properties:
 - HDT: **289°C**
 - Other properties similar to Watershed material

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Stereolithography (SLA)

Source: What's the Difference Between Stereolithography and Selective Laser Sintering?



Polymer based 3D printing (2)

Selective laser sintering (SLS) can be alternative:

- Laser sintering of *polymer powder* (thermoplastic polyamide)
- Based on Nylon / polyamide polymers
 - Typical HDT ~ I50°C
 - Improvements: Aluminum filled PA (Alumide): HDT 169°C, Glass filled PA: HDT 176°C
- Previously not considered due to water absorption
- Recent new material development: Solvay AV-755 (link)
 - PAEK (polyaryletherketone)
 - HDT 278°C
 - Very low water absorption of 0.01%
- Typical challenge for SLS: surface finish
- Interesting material to try out for demonstrator





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Selective laser sintering (SLS)

Source: What's the Difference Between Stereolithography and Selective Laser Sintering?



Other materials considered for 3D printing

- Ceramics can be used for high precision fabrication with good surface finish:
 - Slurry based photo-polymerization (SLA, DLP, TPP) with SiO₂, Al₂O₃, ZrO₂ or SiC show great potential for small scale fabrication with controllable feature size and surface finish
 - Demonstration of 3D microstructures with sub-µm resolution

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- Power based fusion (SLS, SLM) still under development
- Very high temperature resistance: +1400°C
- Interesting option to explore with printing partner
- More expensive than polymer fabrication
- Additive manufacturing with metals also allows very high temperature resistance:
 - Ti: 1660°C
 - Al: 1250°C
 - Stainless steel: I400°C





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Source: ZhangweiChen, et al., 3D printing of ceramics: A review, Volume 39, Issue 4, April 2019, Pages 661-687

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Previous work: bare die impingement in package



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Novel 3D-shaped polymer multi-jet impingement cooler

Outlets

Wei et al., 2017 IEEE IEDM: pp.32-5.



First demonstration of a low-cost polymer-based impingement jet cooler, reported in IEDM 2017

- 4×4 inlet jet array
- 5×5 outlet jet array
- 450 µm inlet nozzles diameter
- Mechanical machining





Wei et al., IEEE Trans. Compon. Packag. Manuf. Technol, 2019 9(9): 1815-1824.

Advantages:

14mm

Small form factor

14mm

Inlets

• More flexible and customizable design

1mm

• Finer resolution of the internal structures

Challenges:

- Excess liquid resin removal
- Material compatibility with coolant
- Structural integrity → bridging of cavities Semiconductor Packaging Laboratory

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Outlet

materialise

Impingement cavity

Inlet

3D printed impingement jet cooling: package level size

Outlet	Inlet tube
tube	
8	2
	1
	A A A A A A A A A A A A A A A A A A A
	a start and a start a st
7	









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Bare die impingement in high-power, large size chip package

80

60

40

20

0

advanced

air cooling

())

Average chip temperature increase







Design I with nozzle array below coolant entrance connection





TSR Heaters 18 • 2 • 1 Z4 **Z3** Z2 Z1 4 - 3 **Z8** Z7 Z6 Z5 Z12 Z11 Z10 Z9 12 11 15 14 Z16 Z15 Z14 Z13

 23×23 mm² test vehicle



Inlet flow **Outlet flow** Additional distribution 8mm

Design 2 with additional distribution layer to improve flow uniformity over

chip surface

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Measurement data – 3 LPM DI water

6.5X improvement

2 mm-pitch

impingement

cooling (exp.)

30%

pitch, corresponding to a chip power density of 175 $W/cm^2 \rightarrow$ The average thermal resistance of the cooling with 3 LPM is 0.065 K/W.

Wei et al., IEEE Trans. Compon. Packag. Manuf. Technol, 2021: 415-425.

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3D printing cooling for different packaging designs

Test case 2

Polymer



(a) (b)Impingement jet region (d) (C) Power density (W/cm²) 60 7 8 0 1 2 3 4 4 5 6 0 $q = 98 W/cm^{2}$ $q = 75 \text{ W/cm}^2$ $q = 62.5 W/cm^2$

Outlet

Inlet

Wei et al., IEEE Trans. Compon. Packag. Manuf. Technol, 2020: 577-589.

Wei et al., Appl. Therm. Eng., 2020, 164, 114535.





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Hotspots targeted cooling

Hot spots

cooling cells

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Additive manufacturing on printed circuit board (PCB)



The bottom-up LCD-based stereolithography machine with a vacuum suction system (includes the vacuum chamber, the protective bottle and the pump)

Fei, Wei et al., 2019 SFF Symposium





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- Need for lower CTE polymers due to current large mismatch with laminate CTE
- Collaboration with KU Leuven to develop the low CTE materials
- Trials with materials with lower CTE
 - Silica and ceramic fillers added to lower CTE
 - Limited filler concentration to keep material printable
- Stereo-DIC technique was used to measure the CTE of four composite materials for 3D printing of impingement cooler.



CTE modified polymer cooler with resin-silica composite

Dimension Change (µm)

125

100 -

75.

50

25

0

-25

-50



The microstructure of resin-silica composite printed at 25°C

Dimensional change with temperature of 3 composite samples (Manufactured under the same conditions with the SEM samples)

Temperature (°C)

50

CTE: coefficient of thermal expansion T_{g} : glass transition temperature

 L_0 : samples' initial length (~10mm)

CTE

50°C

90°C

100

Curve Slope = $\frac{\Delta L}{\Delta T}$

 $\alpha_1: 20.4 \pm 0.7 \text{ ppm/}^{\circ}\text{C}$

The results show that α_1 is close to the CTE of commercial PCB, indicating the part can bond well on the PCB when the IC runs at a temperature below 90°C.





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 $\alpha_2: 60.7 \pm 1.4 \text{ ppm/°C}$

150

200

Glass transition

temperature range

Adhesion properties measurements of resin-silica composite



- Adhesion properties between different part/PCB substrate showed the adhesion on the part-PCB interface depends on their surface interactions.
- The larger the interface roughness, the greater the interaction forces on the contact surface.
- All the pull-off test and pressure test prove the bonding force between part-PCB is strong enough to keep them as an integrity system.





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The influence of surface roughness on adhesion forces.



Fei, Wei et al., 2019 SFF Symposium

Suspension viscosity and particle dispersion of resin-silica composite

Fei, Wei et al., 2019 SFF Symposium



- Regarding the printing material, the silica-resin suspension containing 60 vol.% silica is uniformly enough to ensure the flowability during printing, at the same time, it has a low CTE which is close to that of the PCB material.
- The thermal cycling test indicated the tailored part owned good CTE compatibility with the PCB substrate.





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Variation of the viscosity of silica-resin suspensions with temperature



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Alternative fabrication: Glass cooler

Fabrication of microstructures in glass





Yuksel Temiz, Robert D. Lovchik, Govind V. Kaigala, Emmanuel Delamarche, Lab-on-a-chip devices: How to close and plug the lab?, Microelectronic Engineering, Volume 132, 2015, Pages 156-175,

- Recent developments in glass fabrication enable internal microstructures
- Interesting material properties for our cooler (material: fused silica) :
 - CTE 0.5 ppm/°C \rightarrow more compatible with Si and substrate than polymer
 - High temperature resistance
- Explore feasibility for glass cooler → adapt cooler design for glass microfabrication design rules





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Design considerations: Glass cooler





Design I

- 2 fabrication options:
 - I. Monolithic structure
 - 2. Welding bonding^o
- Designs for both options finished
- Fabrication ongoing





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Design 2

Manufacturability

Resolution	< I µm
Surface roughness	Ra < 100na
Aspect ratio	> 1:500
Glass-to-glass seal withstands	100 bar

Demonstration of the Glass cooler

- Glass has interesting material properties:
 - ' Lower CTE than printed polymers ightarrow more compatible with Si and package
 - High temperature resistance
- Subtractive manufacturing technique used to create complex internal structures:
 - Focused laser beam locally modifies the density inside the glass
 - Cavities created by additional chemical etching
- Demonstrated for cooler geometry: 4x4 nozzle array design







Demonstration of the Glass cooler



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Assembly of the Glass cooler on to the packaging





Wei, Ph.D. thesis, 2020

PTCQPLUS soldered to PCB Glass cooler glued to the package In-/Out-let tubes glued to the glass cooler

Water leakage at the in-let tube connection point



Additional epoxy applied to strengthen tube connections





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Metal 3D-Printed Direct Liquid Jet-Impingement Cooling

- The advantages of metal 3D printing are numerous, such as the improved dimensional stability and the minimum warpage and shrinkage of parts.
- For the specific application it can be mentioned also the reduction of the CTE mismatch between metal cooler and PCB, on the integration and reliability point of view and the not absorption of liquid by the device.
- More in general, 3D printing makes possible to manufacture parts with shapes and geometries that no other techniques can.



Pappaterra, Antonio, et al. "Advanced (Metal 3D-Printed) Direct Liquid Jet-Impingement Cooling Solution for Autonomous Driving High-Performance Vehicle Computer (HPVC)." EuroSimE. IEEE, 202 I





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Metal 3D-Printed Direct Liquid Jet-Impingement Cooling





CTS from the side of the cooler





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Metal 3D-Printed Direct Liquid Jet-Impingement Cooling







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Metal 3D-Printed Direct Liquid Jet-Impingement Cooling





Computed tomography scan (CTS) from the top and picture from the bottom of the chip bonded to the cooler







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CTS nozzles diameters



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Embedded microchannel with 3D manifold Stanford



- Higher *heat transfer coefficient* requires small D_h , Π_{over} , Δp increases \rightarrow system pump power \uparrow
- To reduce Δp , decreasing L using **3D manifold** to deliver cold liquid from the top and collect the hot fluid using U-shape "short" micro-channel
- This results in smaller pressure drop, temperature uniformity, higher heat transfer coefficient, and higher heat flux > 1kW/cm²





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Embedded microchannel cooling for power electronics

Fluidic Cooling	Cold-plate	Ceramic substrate	Chip
	Conventional package with cold plate cooling	Compact package with DBC embedded u-channel cooling	Ultra-compact package with chip embedded u-channel cooling
	chip AIN Ceramic Copper spreader Heat Sink	<pre>chip chip location locati</pre>	Ceramic chip 3D manifold

- Power electronics packaging is different \rightarrow high electrical voltage
- Embedded u-channel inside device needs dielectric liquid
- Ceramic-based channel cooling is promising!





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Package-level ceramic-based microchannel cooling integration for power electronics

POETS project: Heterogeneous SiC Power Modules with DBC Active (laser cut) Microchannel Cooling



- Embedded micro-channels into aluminum nitride substrate
- Heterogenous integration: microbump bonding and through hole vias
- Electrical-thermal co-design
- Single side cooling → future double side cooling



Package-level ceramic-based microchannel cooling integration for power electronics







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Long term thermal measurement

INTRODUCTION

- Objective: long term measurement of the μ cooler
 - Most challenging case: bar die package
 - Identify reliability issues

PROCEDURE

- Duration: 1000h
- Monitor chip temperature
 - Measure every day (24 hours)
- Evaluate cooler geometry:
 - Optical inspection with microscope
 - Measurement at beginning and end of test





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Test chip and test board Courtesy of Global Foundries



Long term thermal measurement MEASUREMENT SET-UP



- Simplified set-up developed for thermal and flow measurement
- Integrated pump and heat exchanger for coolant flow loop
 - Fan control
 - Pump control
 - No flow rate control and measurement, can be estimated
- DI water used as liquid coolant
- No filters used in simplified test
- Temperature measurement in all 25 sensors of test chip

PURDUE UNIVERSITY.



Test board placed in plastic tray to Semiconductor Packaging Laboratory (All-in-one for Semiconductor Packaging, Heat transfer, and Assembly Lab)

Long term thermal measurement

RESULTS



- Test conditions:.
 - Chip power: 30V / 90W
 - Pump voltage: I2V
 - Heat exchanger voltage: 10V
 - Flow rate at 12V: estimation 1.5 L/min
- Cooler performance and room temperature monitored for 50 days

Observations:

- No leakage observed during the test on the bare die package
- Consistent thermal performance during the 50 days \rightarrow small variation
- Similar behaviour for all 25 sensors



Long term thermal measurement

Impact on cooler geometry: nozzle diameter



Bottom view (II x II inlet nozzle array)





Nozzle geometry and nozzle diameter evaluation with 2D and reconstructed 3D microscope image before the long-term measurement





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Long term thermal measurement: impact of cooler nozzles



Observations after long term measurement with DI water for the 3D printed plastic cooler:

- **No clogging** of the nozzles or internal channels despite lack of filters in simple test setup
- No erosion of the nozzles.
 - No significant difference for the nozzle diameters before and after the measurements
 - Discoloration of the cooler material in contact with the cooler

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Defect measurements of 3d printed cooler



Gen-2 printed cooler



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Previous work: bare die impingement in package



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